

3rd
Call for
Papers

The 15th International Symposium on
Measurement Technology and Intelligent Instruments

ISMTII 2023

COEX, Seoul, South Korea

September 17^{Sun.} ~ 20^{Wed.}, 2023

On-site Conference

Organized by

Korea Institute of Machinery & Materials (KIMM)
International Committee on Measurements and Instrumentation (ICMI)

Co-organized by

Korea Advanced Institute of Science and Technology (KAIST)
Korea Research Institute of Standards and Science (KRISS)

Supported by

Korean Society for Precision Engineering (KSPE)

ISMTII 2023

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Conference Format

The ISMTII 2023 is being planned solely for all in-person participation. Later, it may be considered to include an on-site/online hybrid format depending on COVID situations worldwide.

Venue

COEX in Seoul, South Korea

Seoul is the capital of the Republic of Korea. For decades known as the Miracle of the Han, the city kept its head down, barely raising a ripple as the country rebuilt in the decades following the Korean War. Today, Seoul has re-emerged as an economic powerhouse and the epicentre of Hallyu - a Korean wave of culture that is sweeping the world's smartphones, food halls and dance floors. Seoul is now a city where glass and steel towers and the ancient curves of palace roofs coexist, brimming with the brushstrokes of the past and contemporary public arts of tradition and inspiration. At the heart of Seoul, COEX is located as the main convention centre to provide visitors with all the essence of Seoul under one roof including dining and entertainment.



Symposium Scope

The conference will address the role of metrology in technical solutions facing global challenges. The sessions will therefore focus on but are not limited to the following areas:

- Intelligent measurement and instrumentation
- In-process and on-line measurement
- Machine tool metrology
- Material characterization
- Micro/nano-metrology
- Optical metrology and inspection
- Sensors and actuators
- Signal processing and machine learning
- Uncertainty, traceability and calibration
- Frequency comb: fundamentals and applications

Selected papers will be recommended to be published in the **IJPEM** (International Journal of Precision Engineering and Manufacturing), **IJPEM-GT**, **IJPEM-ST**, **NMME** (Nanomanufacturing and Metrology) or **JKSPE** (Journal of the Korean Society for Precision Engineering).

Important Dates

Abstract submission deadline*	March 15, 2023 Due Extension March 31, 2023
Notification of abstract acceptance	April 15, 2023
Paper submission deadline**	May 15, 2023
Notification of paper acceptance***	June 15, 2023

* Abstract (300 words in length) should be written in English using the abstract template on ISMTII 2023 website.

** Authors of accepted abstracts must submit short (2 pages) or long papers (4~6 pages) to ISMTII 2023. The papers should be written using the paper template with texts, figures, tables and references.

*** Authors of selected long papers will be recommended to IJPEM, IJPEM-GT, IJPEM-ST, NMME, and JKSPE for journal publication

Registration Fee

	Early Registration	Late & On-site Registration
Date	By July 15, 2023	
Regular	USD 600 / KRW 720,000	USD 700 / KRW 840,000
Student	USD 300 / KRW 360,000	USD 400 / KRW 480,000
Banquet	USD 100 / KRW 120,000 * 'Student Registration' DOES NOT include 'Banquet'.	

Conference Chairs

- Conference Chair: Dr. Jeong Seok Oh, KIMM
- Honorary Chair: Prof. Seung-Woo Kim, KAIST

ISMTII 2023 website

www.ismtii2023.org



ISMTII 2023 Secretariat

- Secretariat: Prof. Young-Jin Kim, KAIST
- Tel: +82-42-350-8206
- E-mail: **General** ismtii2023@kspe.or.kr
Accounting account@kspe.or.kr
- Add: 291 Daehark-ro, Yuseong-gu, Daejeon, Republic of Korea (34141)

Keynote Speakers



Han Haitjema / Professor

KU Leuven (Belgium)
Department of Mechanical Engineering

Title Metrologic Characteristics and Uncertainty Evaluation of Surface Texture Measurements



Sang-Yoon LEE / CEO

INTEKPLUS (South Korea)

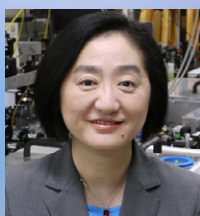
Title Industrial Use Cases of 3D Optical Metrology



Eberhard Manske / Professor

Technische Universität Ilmenau (Germany)
Institute of Process Measurement and Sensor Technology

Title Nanopositioning and Nanomeasuring Machines with a Direct Link to the Unit of Time



Kaoru Minoshima / Professor

University of Electro-Communications (UEC) (Japan)
Department of Engineering Science

Title Precision Measurements beyond Frequency Metrology using Versatile Control of Optical Waves with Optical Frequency Comb



Laura Sinclair / Physicist

National Institute of Standards and Technology (NIST) (USA)
Fiber Sources and Applications Group

Title Pushing the Boundaries of Ranging and Time Transfer Through Precise Control of Optical Frequency Combs



Liandong Yu / Professor

China University of Petroleum (China)
College of Control Science and Engineering

Title Microfluidic Sensor on the Early Diagnostic of Cancer Diseases



Peter de Groot / Chief Scientist, Honorary Professor

Zygo Corporation, University of Nottingham

Title Solutions in manufacturing metrology using interferometry (to be updated)